# D esign of realistic sw itches for coupling superconducting solid-state qubits 

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#### Abstract

Superconducting ux qubits are a prom ising candidate for solid-state quantum com putation. O ne of the reasons is that im plem enting a controlled coupling between the qubits appears to be relatively easy, if one uses tunable Josephson junctions. W e evaluate possible coupling strengths and show, how much extra decoherence is induced by the subgap conductance of a tunable junction. In the light of these results, we evaluate several options of using intrinsically shunted junctions and show that based on available technology, Josephson eld e ect transistors and high-T c junctions used as -shifters would be a good option, whereas the use of $m$ agnetic junctions as -shifters severely lim its quantum coherence.


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[^0]Q uantum com putation prom ises qualitative im provem ent of com putationalpow er as com pared to today's classical com puters. A n im portant candidate for the im plem entation of a

 setups involves engineering of couplings and decoherence, see e.g. [5], ].

To perform universal quantum computation with a system of coupled qubits it is very much desirable to be able to sw itch the couplings (although there are in principle workarounds $\left.\left[\frac{\sigma_{1}}{1}\right]\right)$. It has already been described that for ux qubits, this can be achieved by
 i.e. a superconducting sw itch, as shown in Fig.i'i.'. The prim ary and $m$ ost straightforw ard proposal for the implem entation of this sw itch is to use an unshunted DC-SQU $\mathbb{D}$ based on tunnel junctions utilizing the sam e technology as for the qubit junctions. A though this holds the prom ise of inducing very little extra decoherence, it su ers from tw o practical restrictions: i) the SQU $\mathbb{D}$ loop has to be biased by exactly halfa ux quantum in the o-state and ii) the extemal control param eter is a m agnetic ux, which introduces the possibility of ux cross-talk between the qubits and the switch. The combination of i) and ii) implies that even $s m$ all ux cross-talk will severely perturb the o-state of the sw itch.

This can be avoided by using di erent Sw itches: A voltage-controlled device such as a Josephson Field E ect Transistor (JoFET) ) , in or an SN S-T ransistor com pletely avoids the cross-talk problem. As an interm ediate step [ $[-\overline{8}]$, one can im prove the SQU D by using a large Junction, in order to $x$ the $O$-state at zero eld. Such -junctions can be found
 dam ped by a large subgap conductance because they contain a large num ber of low-energy quasiparticles.

In this letter, we quantitatively evaluate the coupling strength betw een tw o qubits coupled by a switchable ux transform er. W e evaluate the strength of the decoherence induced by the subgap current m odeled in term s of the RSJ m odel. B ased on this result, we assess available technologies for the im plem entation of the switch.

W e start by calculating the strength $K$ of the coupling between the tw o qubits w ithout a sw itch and then show how it is m odi ed by the presence of the sw itch. From Fig. 'in and the law ofm agnetic induction we nd the follow ing equations for the ux through qubit 1
and 2 induced by currents in the qubits and the ux transform er
$w$ here $M_{Q Q}$ is the self-inductance of the qubits (assum ed to be identical), $M_{T_{Q}}$ is the $m$ utual inductance betw een the transform er and the qubits and the $m$ utual inductance betw een the qubits is assum ed to be negligible. The uxes in Eq. (1) are the screening uxes in the transform er and the two qubits, i.e. the deviations from the extemally applied values. \left. H enceforth, we abbreviate Eq. ( ${\underset{1}{1}}_{1}^{1}\right)$ as $\sim=$ M I. These form ulas are general and can be applied for any ux through the transform er loop. It is $m$ ost desirable to couple zero net ux through the devioe, which can be achieved by using a gradiom eter con guration in For this gradiom eter case, we get $I_{S}=\left(M_{T Q}=M_{T T}\right)\left(I_{1}+I_{2}\right)$, which we m ight insert into (1기) and nd for the inductive energy

$$
\begin{equation*}
E_{\text {ind }}=M_{Q Q} \frac{M_{T Q}^{2}}{M_{T T}}\left(I_{1}^{2}+I_{2}^{2}\right) \quad \frac{M_{T Q}^{2}}{M_{T T}} I_{1} I_{2} . \tag{2}
\end{equation*}
$$

The term s resulting from the o-diagonal elem ents of (in) can directly be identi ed as the interqubit coupling strength $K=2\left(M_{T Q}^{2}=\mathrm{M}_{\mathrm{TT}}\right) \mathrm{I}_{1} \mathrm{I}_{2}$ which enters the $\wedge_{\mathrm{z}} \quad \hat{\mathrm{z}}_{\mathrm{z}}$ Ising-coupling described in Refs. [E-in Josephson energies [《̄ㄴ], to which the diagonal term is only a m inor correction.

W e now introduce the tunable Josephson junction into the loop. U sing uxoid quantization, we rew rite the Josephson relation (ī1). The resulting nonlinear equation can be solved in the follow ing cases: i) If $j_{\mathrm{s}}=I_{\mathrm{c}} j \quad 1$
 $M_{T T}+L_{k i n}(0)$. This can be understood as an e ective increase of the self-inductance of the loop by the kinetic inductance of the Josephson junction at zero bias. ii) In the case $I_{s}=I_{c} j 1, \backslash \circ$ " state, the circulating current is close to the critical current of the sw $\operatorname{itch}$, hence the phase drop is $=2$ and we nd an analogous form $\mathrm{K}=2\left(\mathrm{M}_{\mathrm{T}}^{2}=\mathrm{M}{ }_{\mathrm{TT}}^{0}\right) \mathrm{I}_{1} \mathrm{I}_{2} \mathrm{w}$ th $M_{T T}^{0}=M_{T T}+\left({ }_{0}=4 \mathcal{J}_{\mathrm{C}} j\right)$, i.e. at low $I_{C}$ the coupling can be arbitrarily weak due to the enorm ous kinetic inductance of the junction close to the critical current.

W e now tum to the discussion of the decoherence induced by the subgap conductance of the tunable junction. The decoherence occurs due to the ux noise generated through the
current noise from the quasiparticle shunt. H ence, both qubits experience the sam e level of noise. The decoherence of such a setup has been extensively studied in R ef. [1̄2̄] as a function of the environm ent param eters. In this letter, we evaluate these environm ent param eters for our speci c setup.

W e m odel the junction by the RSJ.m odel for a sound quantitative estim ate of the tim e scales even though the physics of the subgap conductance is usually by farm ore subtle than that. $W$ e evaluate the uctuations of the current between two points of the ux transform er loop sketched in gure ${ }_{1} \mathbf{N}_{1}$. $L$ is the geom etric inductance of the loop, $L_{J}$ is the Josephson inductance characterizing the Josephson contact and $R$ is the shunt resistance. The correlation is given by the uctuation-dissipation theorem h I Iị = coth (h!=2)h!ReY (!), where $Y(!)$ is the adm ittance of the e ective circuit depicted in $F$ ig. 'in. Follow ing the lines of Ref. 氙], this translates into a spectral function of the energy uctuations of the qubit of the shape $h \quad(t) \quad(0)!i=J(!)$ coth $\left(h!=2 k_{B} T\right)$ with $J(!)=\quad!^{2}=\left(!{ }^{2}+!_{c}^{2}\right)$ with the im portant result that the dim ensionless dissipation param eter here reads

$$
\begin{equation*}
=\frac{4 \mathrm{I}_{\mathrm{cir}}^{2} \mathrm{M}_{\mathrm{TQ}}^{2} \mathrm{~L}_{\mathrm{J}}^{2}}{\mathrm{hR}\left(\mathrm{~L}+\mathrm{L}_{J}\right)^{2}} \tag{3}
\end{equation*}
$$

and a cuto $!_{c}=R\left(L+L_{J}\right)=L L_{J}$. Here, $L_{J}={ }_{0}=2 I_{C}$ is the kinetic inductance of the junction. From ( $\left(\frac{1}{-1}\right)$ we receive in the lim it $L \quad L_{J}$ the expression $/ 1=R I_{c}^{2}$ and for $L \quad L_{J}$, L $L_{J}$ it follow sthat / 1=R. From the results ofR ef. poses an upper bound for gate operations to be com patible with quantum error correction. In the follow ing sections we will evaluate for di erent types of junctions in the sw itch, a JoFET, an SFS junction and a high $-T_{c}$ junction by inserting typical param eters. W e use the norm al resistance $R_{N}$ to estim ate the shunt resistance in the RSJ model. Here, it is im portant to note that the param eters $I_{c}$ and $R_{N}$ of the junction determ ine the suitability of the device as a (low-noise) sw itch, which are given by a com bination of $m$ aterial and geom etry properties. In the follow ing we exem plify the calculation of the dissipative e ects w ith several experim ental param eter sets.

Forpresent day qubit technology [1]-1] we can assum eL $\quad 1 \mathrm{nH}$, Eirc $\quad 100 \mathrm{nA} \mathrm{M}_{\mathrm{TQ}} \quad 100$ pH . In the follow ing, we estim ate for a number of junction realizations, adjusting the junction area for su cient critical current.

A Josephson eld-e ect transistor (JoFET) can be understood as an SNS junction where the role of the nom alm etal is played by a doped sem iconductor. By applying a gate voltage,
it is possible to tune the electron density of the sem ioonductor.
The critical current of such a junction containing $\mathrm{N}_{\mathrm{ch}}$ channels can be found using the
 point-contact resistance. In a JoFET, the back gate essentially controls $N_{c h}$. The typical norm al resistance is around $R_{N} \quad 10$. For a JoF ET the critical current of the Josephson junction is $I_{C} \quad 30 \mathrm{~A}$ and the Josephson inductance is $\mathrm{L}_{J} \quad 11 \mathrm{pH}$ '[1] [1].

Inserting the above estim ates we get 7 10.This $m$ eans that the dissipative e ects are weak and a JoFET should be a reasonable $s w$ itch that poses no new constraints. Besides the obvious technologicalchallenge $[\underline{\underline{i}} \boldsymbol{i}$, one draw back of JoF E T s is that due to w ide junctions w ith dim ensions of around $\mathrm{w}=500 \mathrm{~nm}$ they are likely to trap vortices, which can cause $1 / \mathrm{f}$ noise by hopping between di erent pinning sites. H ow ever, this can be reduced by pinning e.g. by perforating the junction.

If we go aw ay from the \on" state w ith the JoFET, we reduce both $I_{C}$ and $G_{N}$ linearily by depleting the density of states. Fig. 'ī1 ' show sthat we nd that the dissipative e ects are strongest during the $s w$ itching process when $L_{J}\left(e_{e}={ }_{e}^{o n}\right) \quad L_{J ; 0}$, and not in the \on" state of the sw itch. In the \o " state of the switch (for e(0)! 0) also goes to zero. If the sw itch is tuned from the \o " state to the \on" state, reaches a localm axim um and then decreases again. This makes the JoFE T a very attractive sw itch: It induces an acceptably low leveldecoherence in the \on" state and can be m ade com pletely silent in the \o " state.

An SFS junction in the -state is based on a $m$ etallic $m$ aterial, thus the estim ate of the shunt resistance in the R SJ m odel yields a much sm aller result than in the case of the
 leaving the transform er properties unchanged, we nd $L_{J} \quad 1: 7 \mathrm{pH} . \mathrm{U}$ sing these estim ates the strength of the dissipative e ects is of the order of $0: 16$. This m akes such a devige unsuitable at the present level of technology, how ever, 五 appears that SIFS junctions are by far closer to the desired values, see Fig.'in'.

H igh $-T_{c}$ junctions can be realized in di erent ways. Here, we take from Ref. param eters for a typical noble $m$ etal (A u)-bridge junction with a $m$ thidkness of about w 100 nm . The product $I_{C} R_{N} \quad 1 \mathrm{mV}$ and ${ }_{N}=8: 3 \mathrm{~nm} . \mathrm{W}$ e assume that in principle $I_{C}$ for the -state and the 0-state are the sam e. For a contact area of around $30 \times 30 \mathrm{~nm}^{2}, \mathrm{I}_{\mathrm{c}} 1$ $m A$ and $R_{N} \quad 1$. Now the strength of the dissipative e ects is easily evaluated to be 6:5 18, which is way better than SFS -junctions and even better than the JoFE T .

W e estim ated the strength of the dissipative e ects that will occur due to the sw itch for several possible sw itches. These results are sum $m$ arized in gure 'A'ي' for typical param eters of the analyzed system s. We nd that the noise properties of JoFET and -shifters based on H igh $-\mathrm{T}_{\mathrm{c}} \mathrm{m}$ aterials introduce no im portant noise sourœe. On the other hand, the param eters found from -shifters based on $m$ agnetic $m$ aterials are $m$ uch less encouraging.

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FIG. 1: T he ux transform er inductively couples two ux qubits $\underset{\underline{2} \boldsymbol{p} .1}{ }$. It can be sw itched, e.g. by a D C-SQU ID or by a tunable shunted Josephson junction.


FIG. 2: Equivalent circuit diagram of the $u x$ transform er circuit. The JoFET is modeled by a resistively shunted Josephson junction.


FIG. 3: The dim ensionless dissipation param eter as a function of the electron density in the 2D EG for a JoFET. The inset show sa linear plot of the region w the largest .


F IG . 4: Log-log plot of norm alstate resistance versus the critical current of the junction. H ere $\mathrm{R}_{\mathrm{N}}$ is taken as an estim ate for the shunt resistance of the junction. The solid line denotes $=10{ }^{6}$ and the two dotted lines are for $=10^{4}$ (lower line) and $=10^{8}$ (upper line). Param eters for the SIF S-junction are $I_{C} \quad 8: 5 \quad 10^{5} \mathrm{~A}$ and $R_{N} \quad 250 \mathrm{~m}$ [50.


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